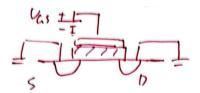
# Day2 MOS Characteristics I

zrrraa

#### 2023.11.13

# Behavour of Channel

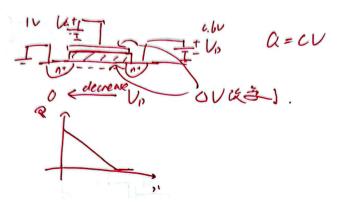
Case I:  $V_{GS} > V_{TH}, V_D = V_S = 0$ 



$$V_{GS} > V_{TH}, V_D = V_S = 0$$

MOSFET turned on, but has no current.

Case II:  $V_{GS} > V_{TH}$ ,  $V_D > V_S = 0$ 

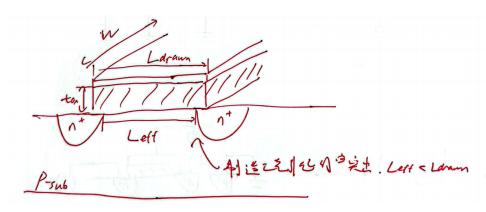


$$V_{GS} > V_{TH}, V_D > V_S = 0$$

When  $V_D$  is applied, A voltage drop occurs between the S and D, resulting in the voltage between the upper and lower plates not being equal to the  $V_G$ . It decreases from the D to the S.

With Q = CV, we can draw a Q-X relationship diagram. That indicates  $I_D$  is related to  $V_{DS}$ .

## **Dimensions of MOSFET**



Dimensions of MOSFET

Affected by the manufacturing process, the n-type semiconductor and silicon dioxide oxide layers at both ends overlap a little. We call this length  $L_{eff}$ , and the length of the gate metal plate is called  $L_{drawn}$ .

# Derivation of I/V Characteristic

### Channel Charge Density

Case I:  $V_{GS} > V_{TH}, V_D = V_S = 0$ 

 $Q_{ch,total} = W * L_{eff} * C_{ox} * (V_{GS} - V_{TH})$ 

We call  $V_{GS} - V_{TH}$  the overdrive voltage,  $C_{ox}$  the capper of unit area.

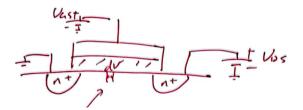
 $Q_{ch,density} = W * C_{ox} * (V_{GS} - V_{TH})$ 

Case II:  $V_{GS} > V_{TH}, V_D > V_S = 0$ 

 $Q_{ch,density} = W * C_{ox} * (V_{GS} - V_{TH} - V(x))$ 

V is x-dependence, see the Behavour of Channel's Case II.

### **Drain Current**



Calculate drain current

We just mentioned that if a voltage is applied to the drain, a current will be generated.

We know that  $v = \mu_n E$ ,  $E = -\frac{dV}{dx}$ .

So we get  $v = -\mu_n \frac{dV}{dx}$ .

From  $Q_{ch,density} = W * C_{ox} * (V_{GS} - V_{TH} - V(x)),$ 

Select a unit length, we get

$$I_D = -v * Q_{ch,density} = -[-\mu_n \frac{dV}{dx} * W * C_{ox} * (V_{GS} - V_{TH} - V(x))]$$

Note that  $I_D$  is a constant.

Move dx to the left and integrate both sides of the equation, we get

$$\int_{0}^{L} I_{D} dx = \mu_{n} * W * C_{ox} * \int_{0}^{V_{DS}} (V_{GS} - V_{TH} - V(x)) dV$$

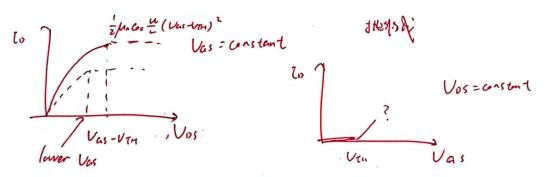
L in these equations always refers to  $L_eff$ .

Simplify the equation, we get

$$I_D = \mu_n * C_{ox} * \frac{W}{L} [(V_{GS} - V_{TH}) * V_{DS} - \frac{1}{2} V_{DS}^2]$$

Pay attention  $V_{GS} \geq V_{TH}$  here.

Then we can get their relationship curves.



The relationship between  $I_D$ ,  $V_{DS}$  and  $V_{GS}$ 

Now we haven't known how the  $I_D$  change if  $V_{DS} > V_{GS} - V_{TH}$  or  $V_{GS}$  increases.

## Link

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